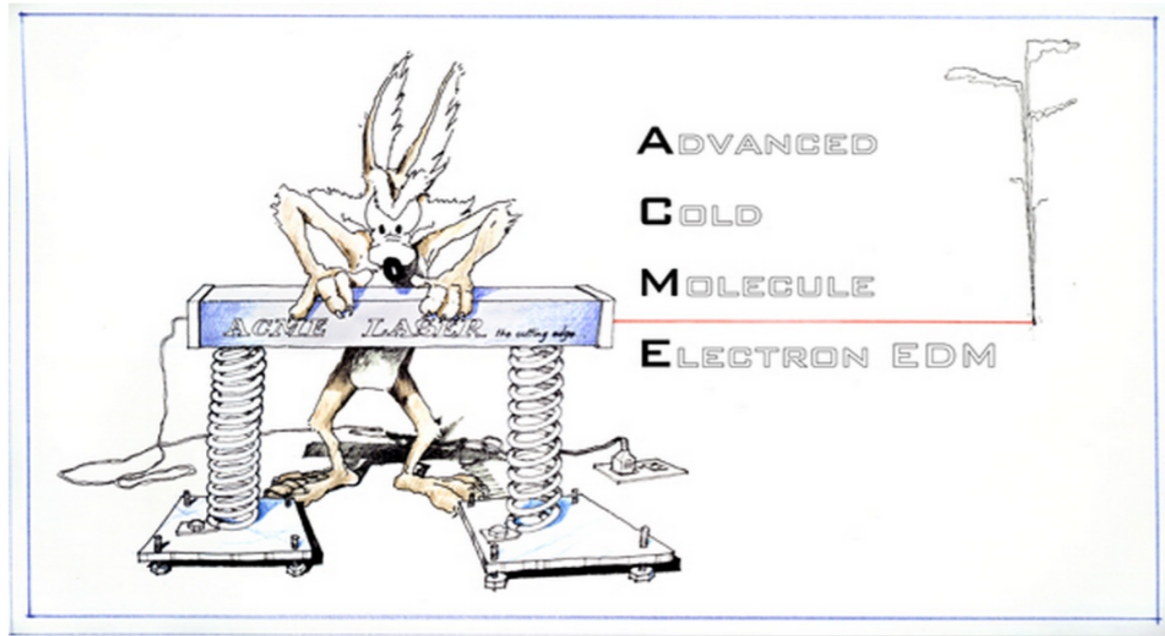


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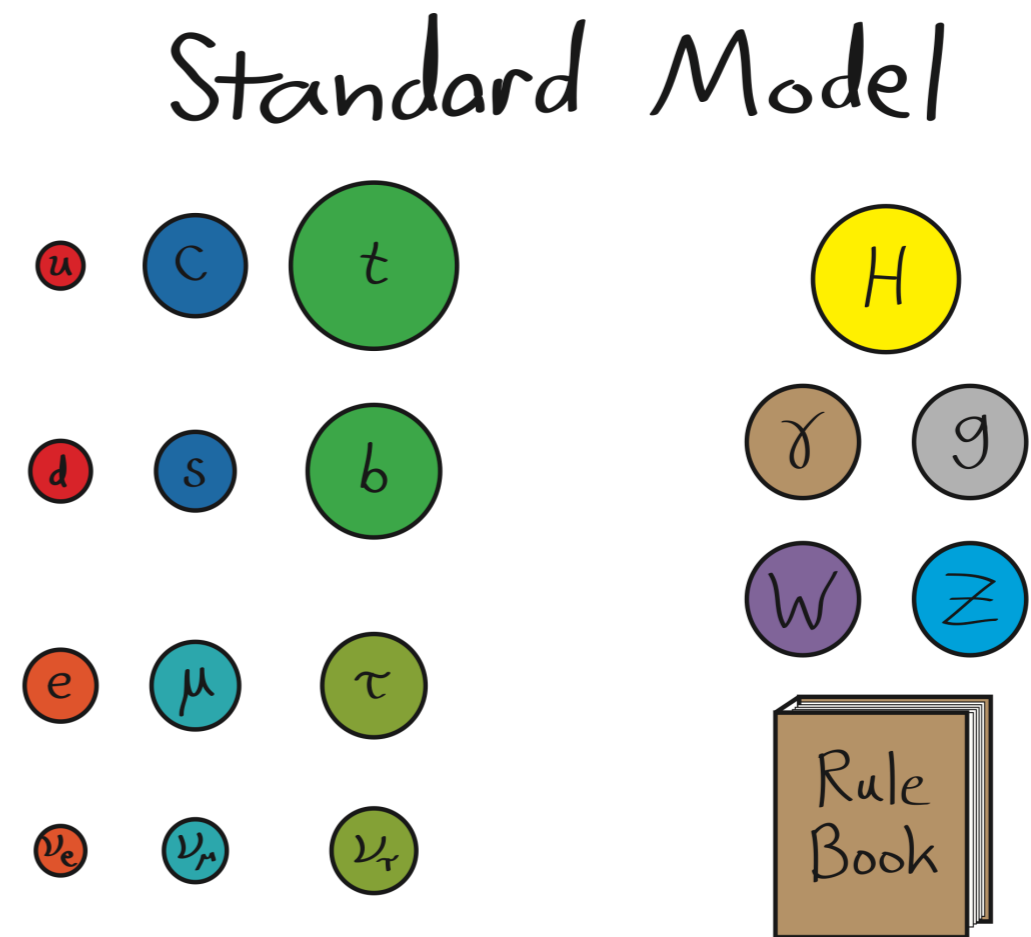
COLE MEISENHOLDER
DAMOP 2020

**THE ADVANCED ACME SEARCH FOR THE
ELECTRON ELECTRIC DIPOLE MOMENT**

SECTION I: WHY ARE EDMS INTERESTING?

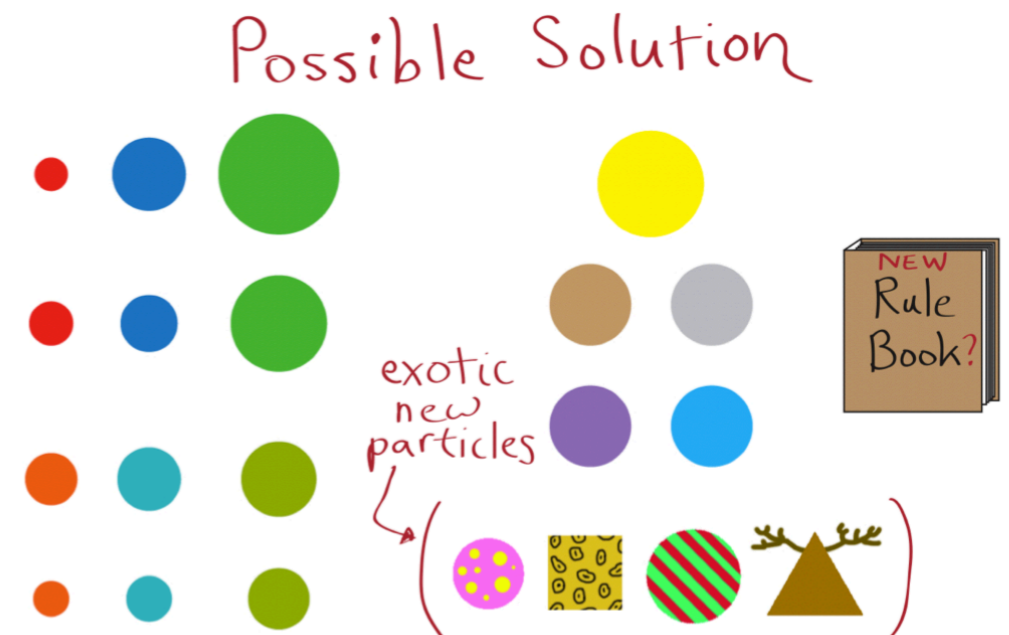
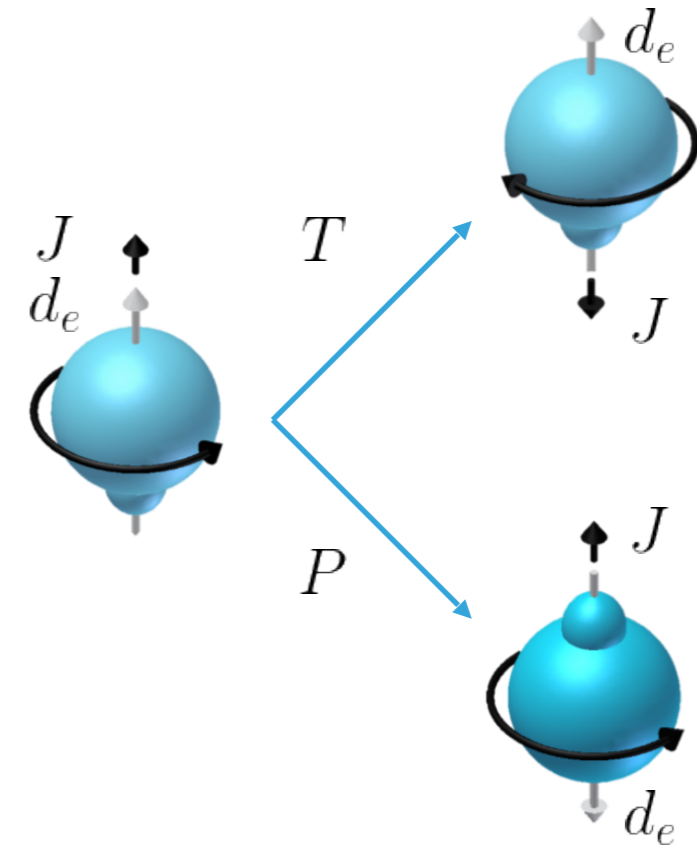
MOTIVATION

- ▶ The Standard Model cannot answer all questions
- ▶ Matter-Antimatter Asymmetry Problem
- ▶ Sakharov conditions allow for baryon asymmetry

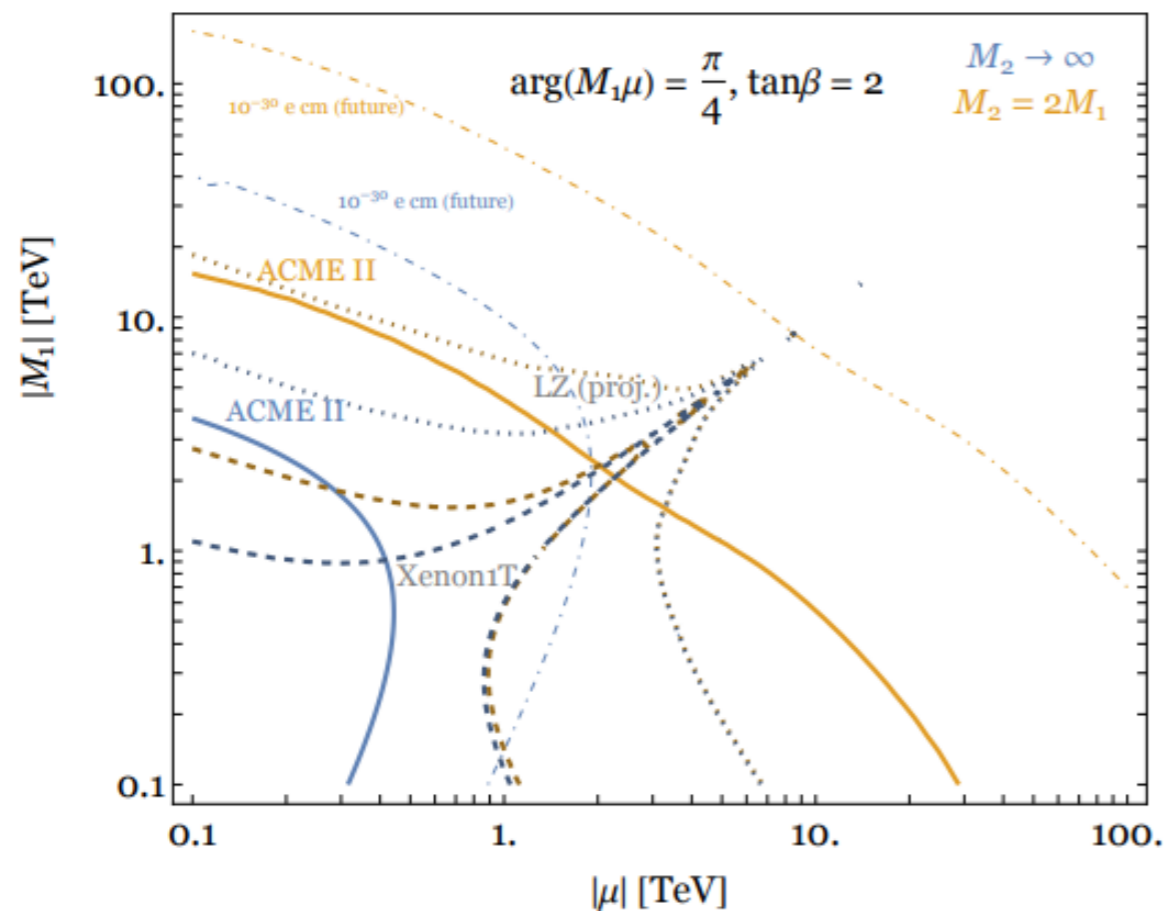


EDMS AND CP VIOLATION

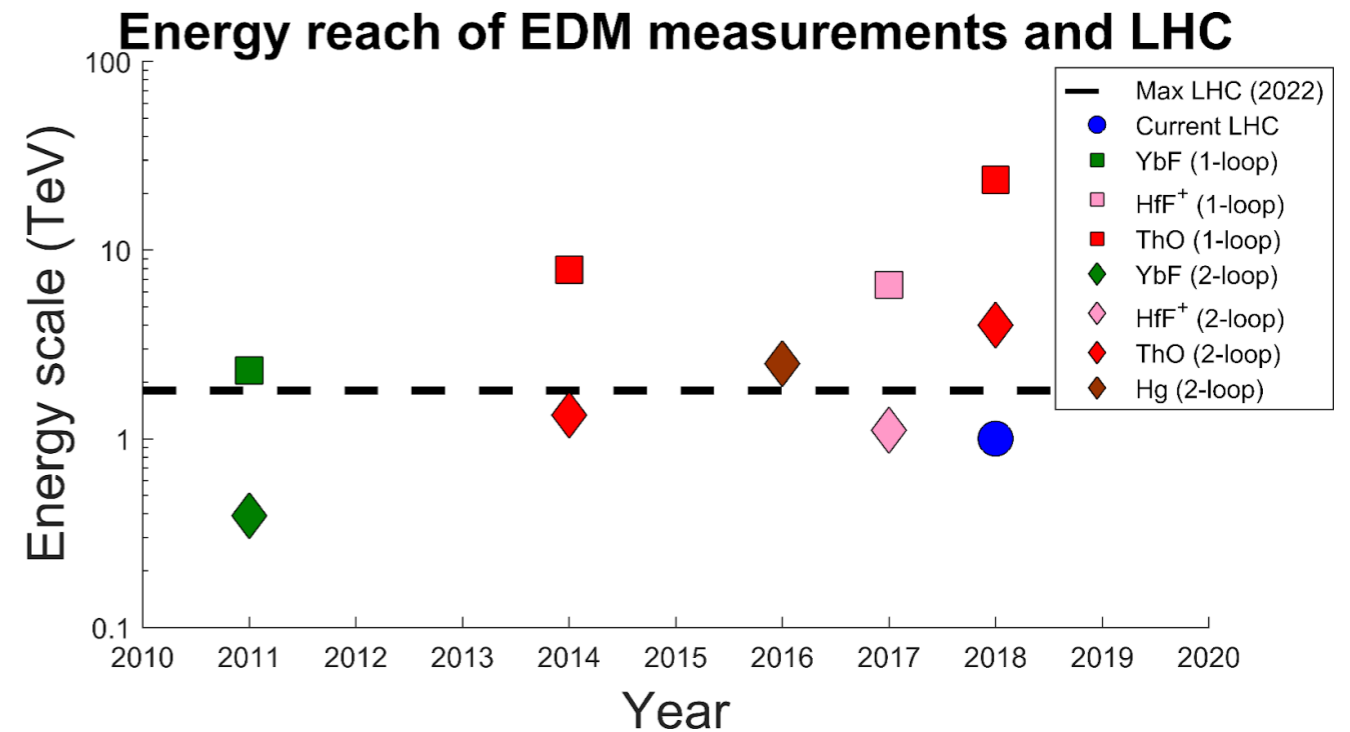
- ▶ Standard Model does not account for the observed asymmetry
- ▶ Permanent EDMs inherently violate P and T
- ▶ Standard Model predicts electron EDM $< 10^{-38} e \cdot cm$
- ▶ Current limit: $|d_e| < 1.1 \times 10^{-29} e \text{ cm}$
- ▶ Many BSM theories predict nonzero eEDMs near our sensitivity



PLACING LIMITS ON NEW PHYSICS



SUSY particle bounds from the ACME II result. Fig. from Matt Reece (unpublished). Advanced ACME projection ($\sim 10^{-30}$ e cm) dashed.



Key EDM results since 2010. Two-loop sensitivity from Nakai & Reece (2017). One-loop sensitivity from Feng (2013). LHC scale gives stop mass sensitivity.

SECTION II: HOW CAN WE MEASURE AN ELECTRON EDM?

AN EDM IN THO

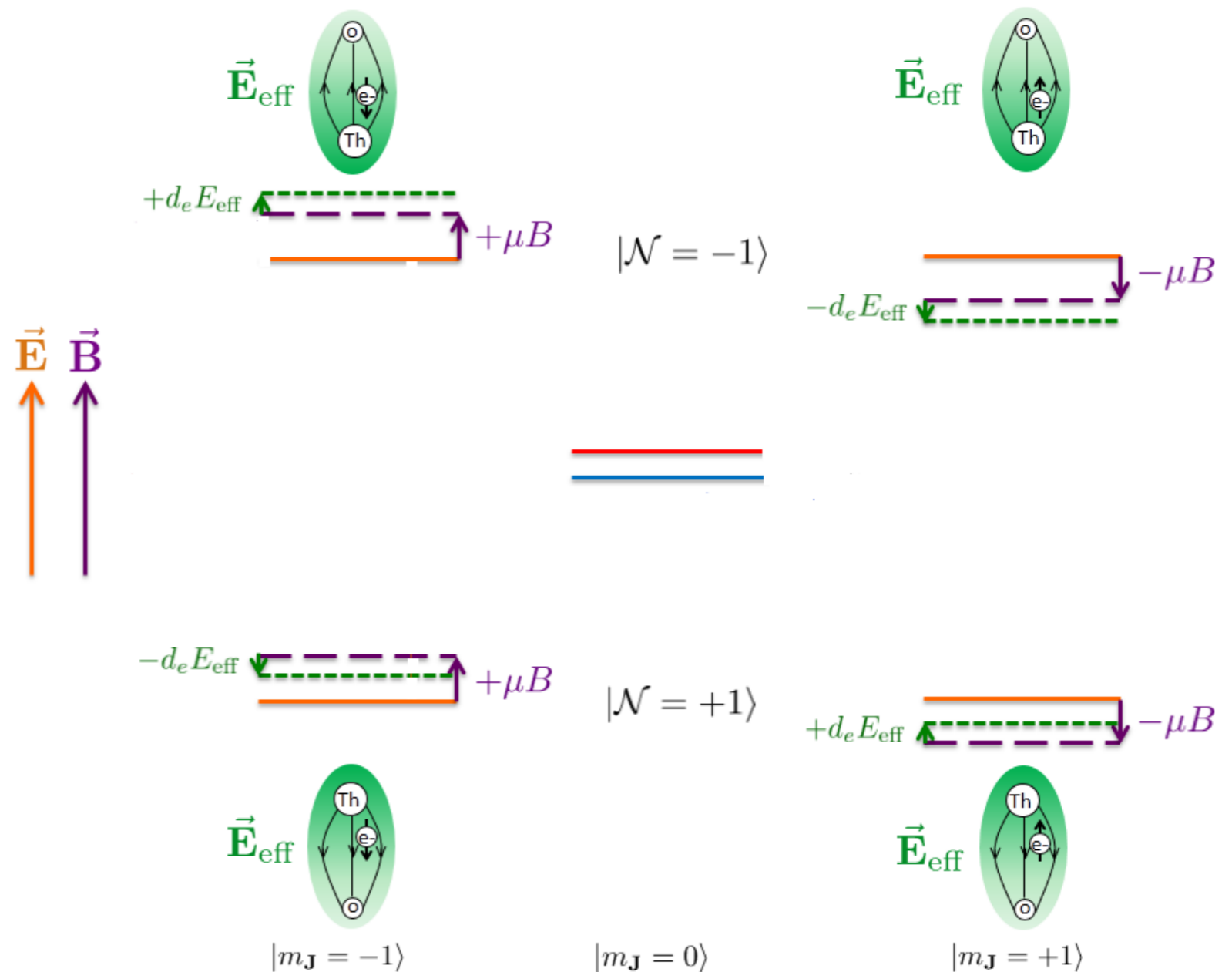
- ▶ Molecules can provide strong internal electric fields

- ▶ ThO has $E_{\text{eff}} \sim 80 \text{ GV/cm}$

- ▶ We can flip this electric field by probing different states

- ▶ Powerful method for eliminating systematic errors

- ▶ ThO only requires a small applied field



EXPERIMENTAL SENSITIVITY

- ▶ For a shot noise limited measurement we

$$\delta\omega \propto \frac{1}{\tau\sqrt{\dot{N}T}}$$

τ = Coherence time

\dot{N} = Count rate

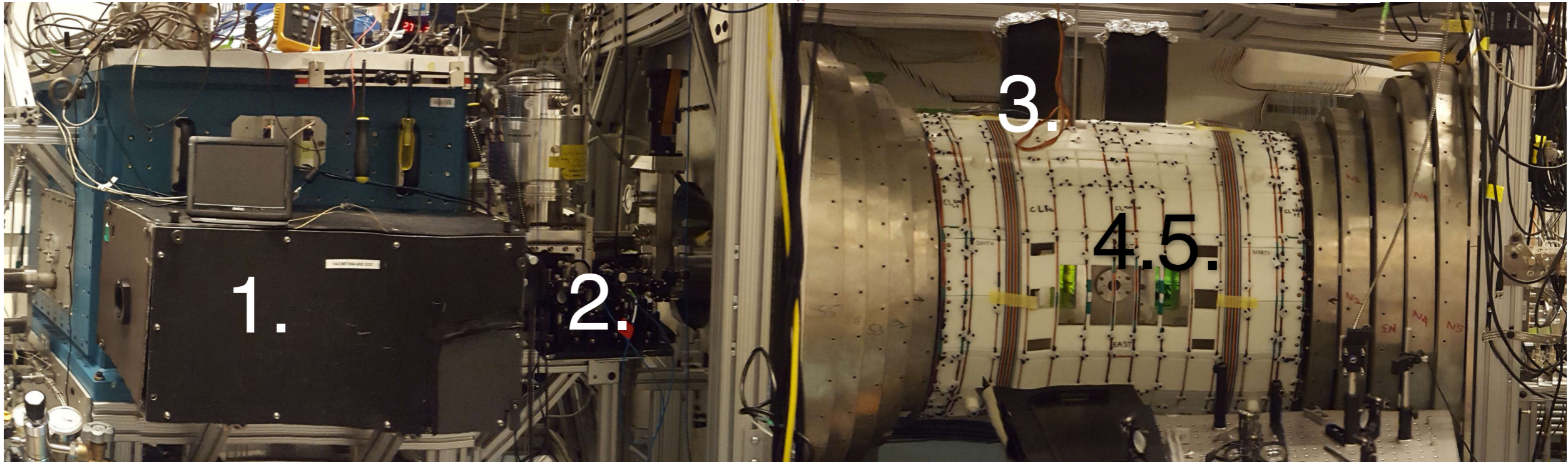
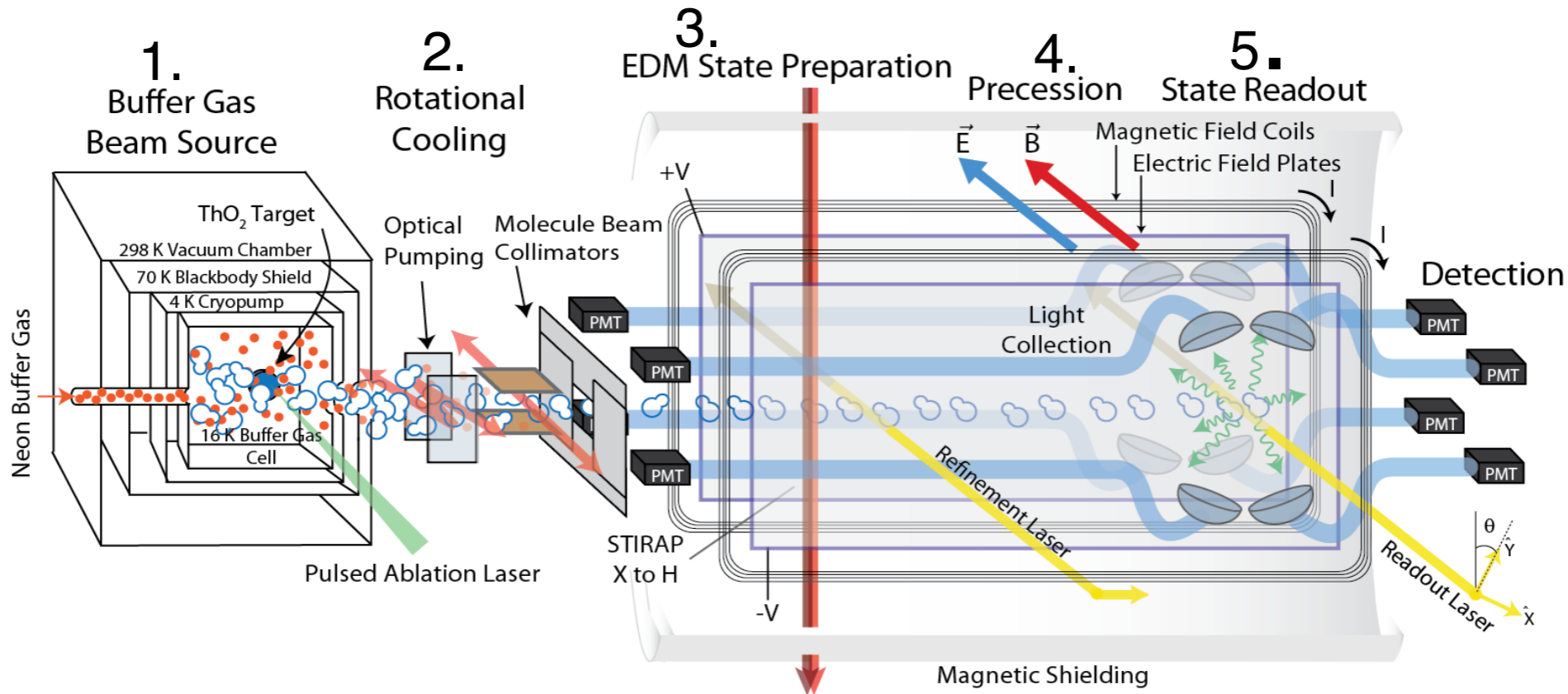
T = Averaging time

- ▶ For our experiment we have $\mathcal{H}_{EDM} = -\vec{d}_e \cdot \vec{\mathcal{E}}_{eff}$

$$\delta d_e \propto \frac{1}{\mathcal{E}_{eff}\tau\sqrt{\dot{N}T}}$$

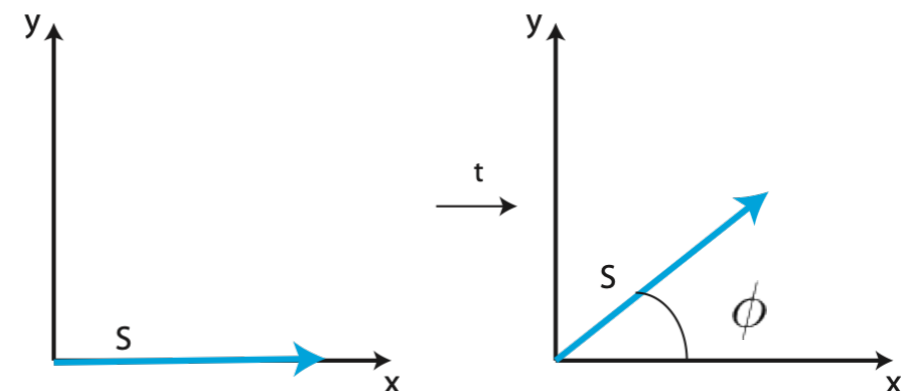
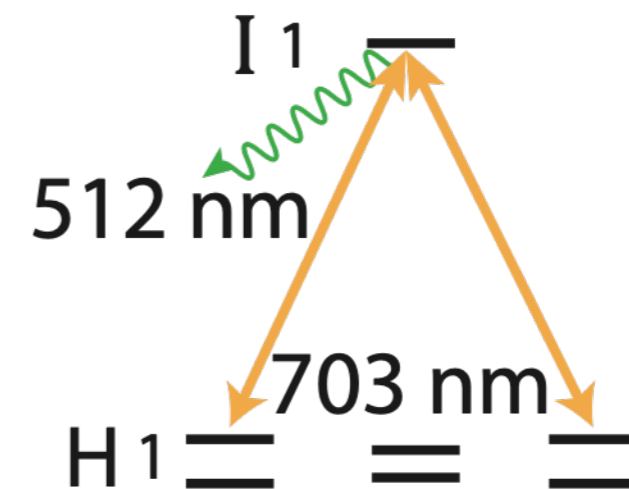
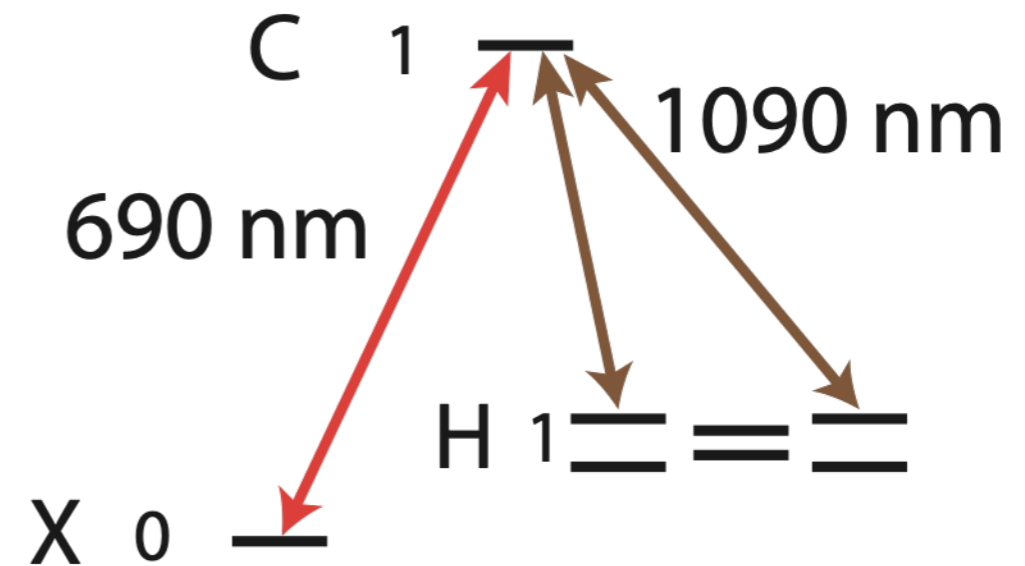
\mathcal{E}_{eff} = Electric field

EXPERIMENT STRUCTURE



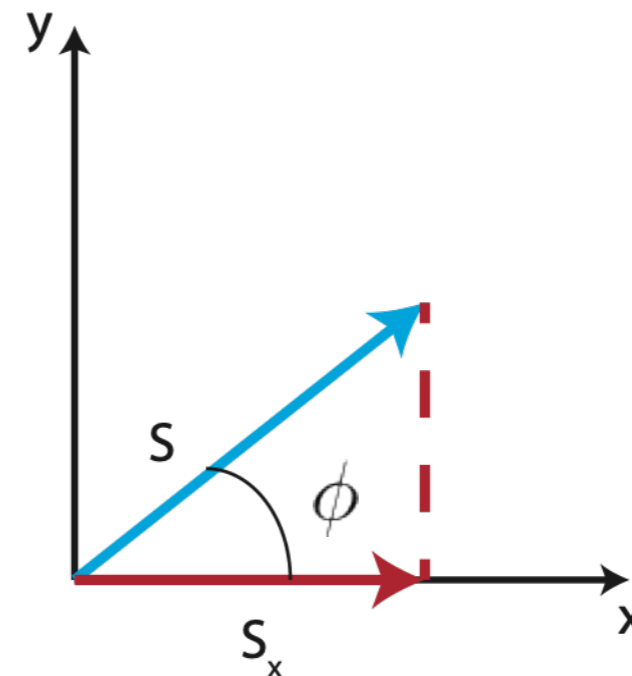
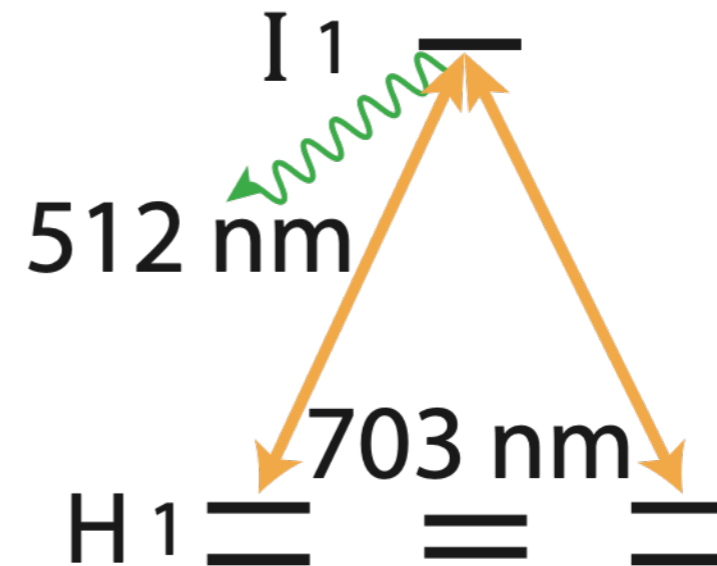
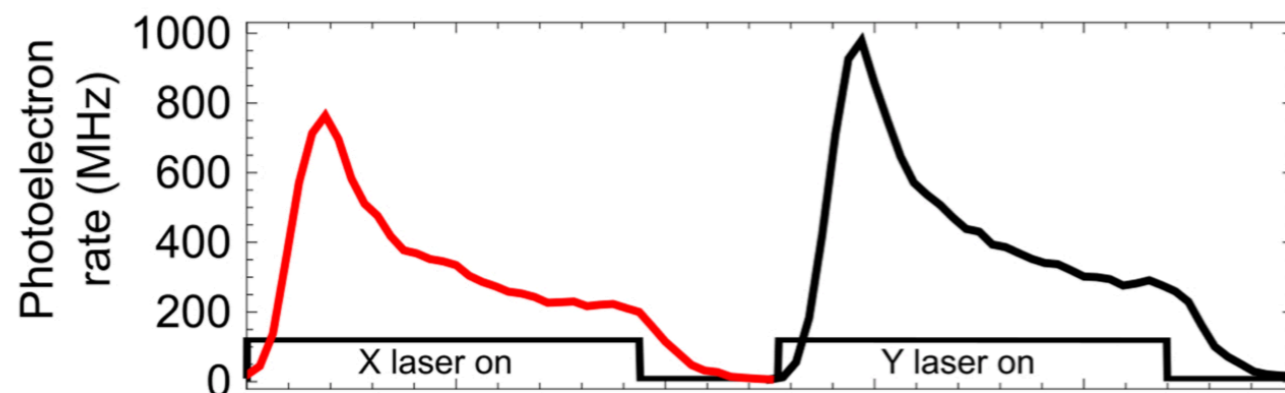
STATE PREPARATION

- ▶ Stimulated Raman Adiabatic Passage (STIRAP)
 - ▶ Coherent population transfer from X to H
 - ▶ ~75% transfer efficiency
- ▶ State Refinement
 - ▶ Optically pump into dark state with desired polarization
 - ▶ Suppress residual STIRAP phases



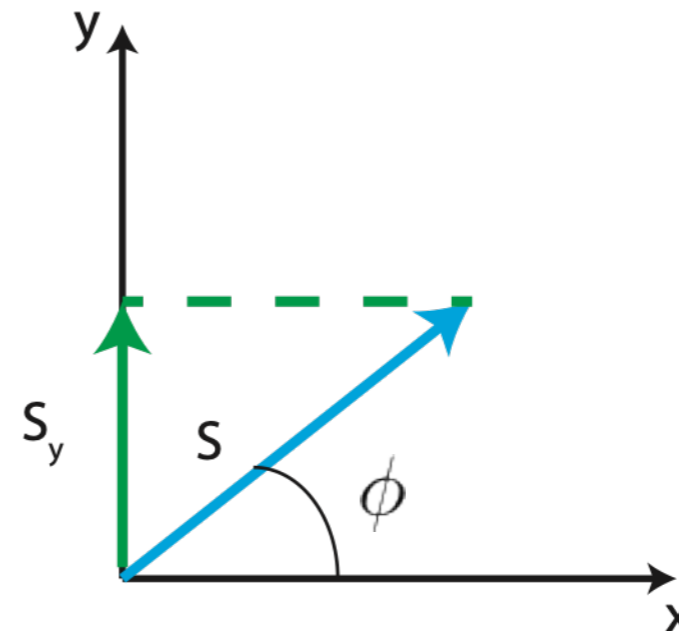
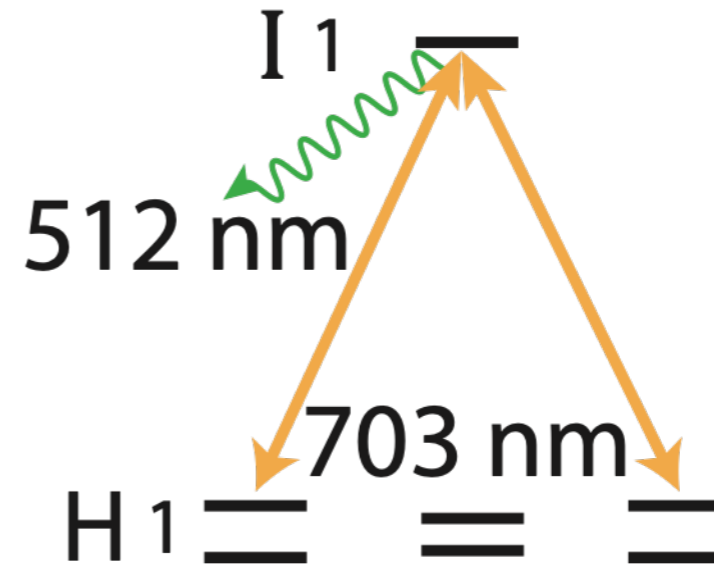
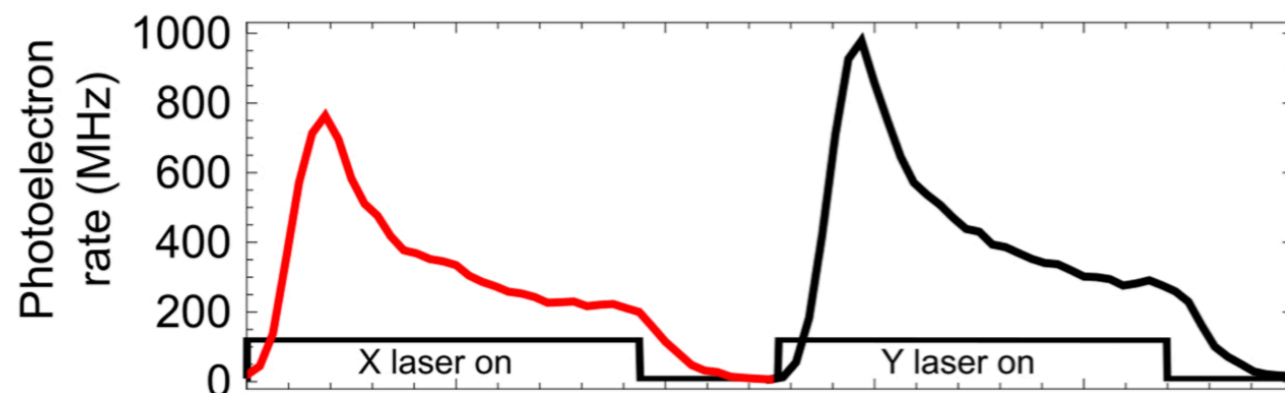
STATE READOUT

- ▶ Project phase onto orthogonal polarizations
- ▶ Rapidly switch polarization at 200 kHz
 - ▶ AOMs allow rapid switching
- ▶ Detect fluorescence with 8 PMTs



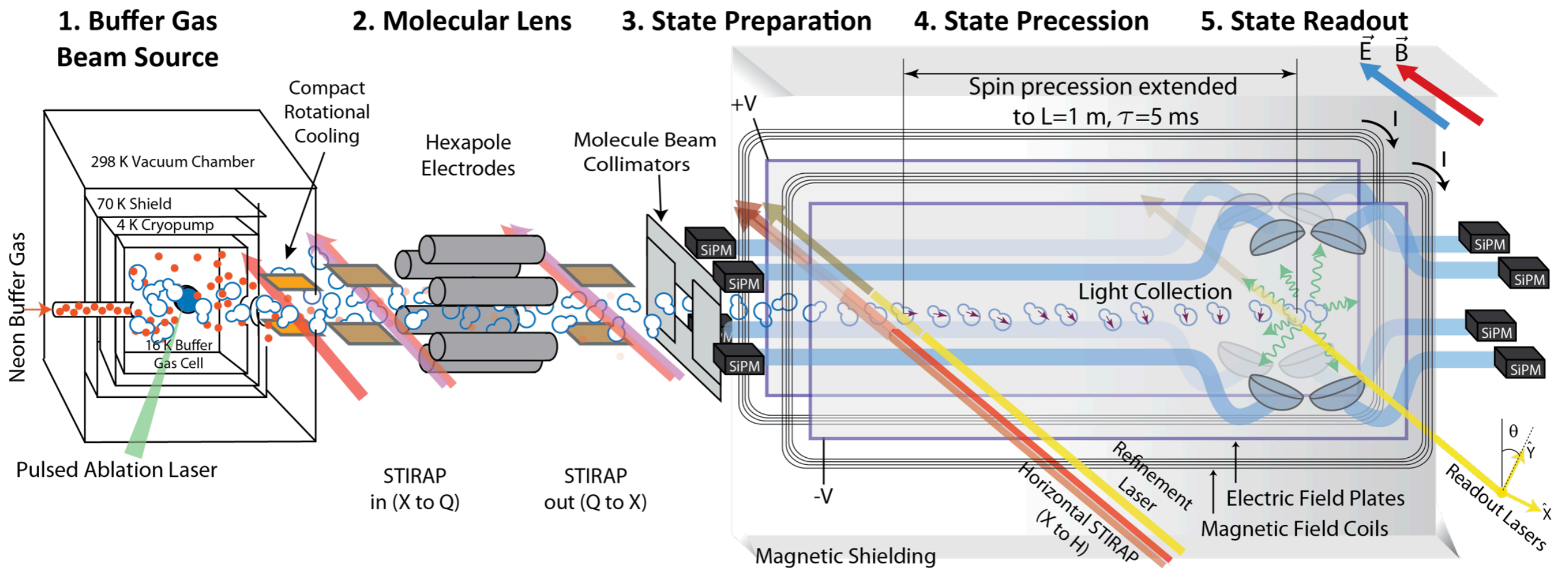
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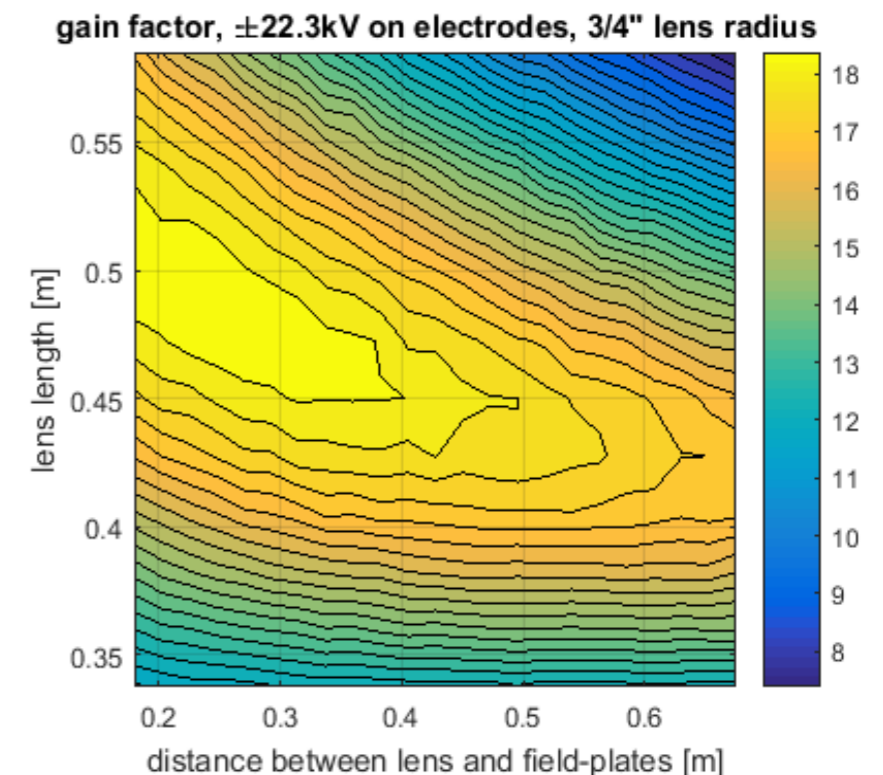
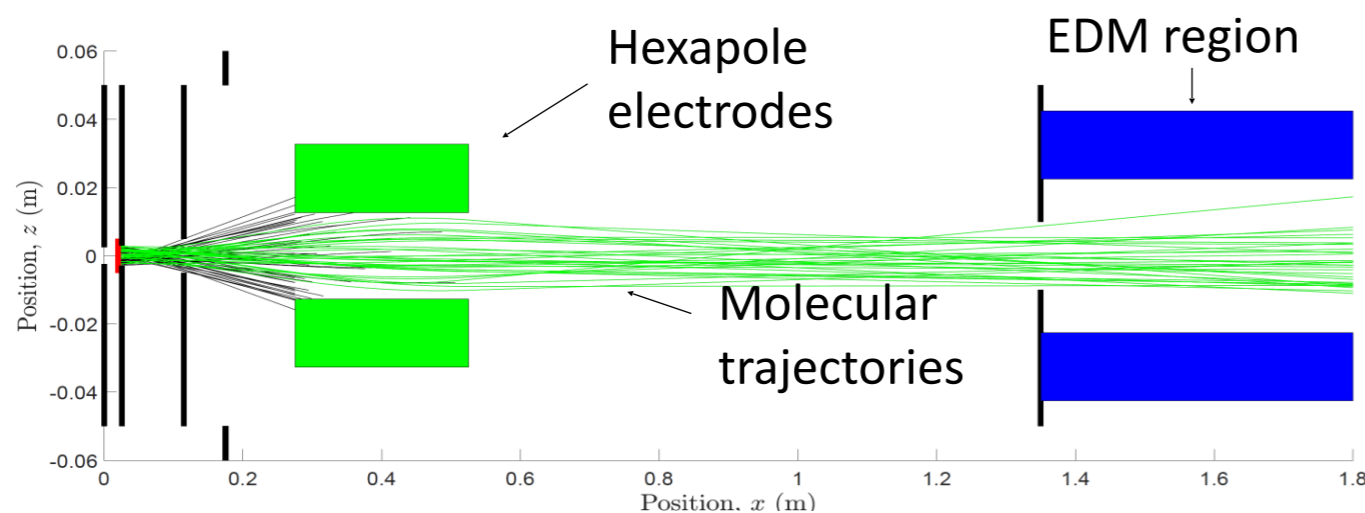
SECTION III: THE ADVANCED ACME EXPERIMENT

ADVANCED ACME OVERVIEW



ELECTROSTATIC LENS FOR THO MOLECULES

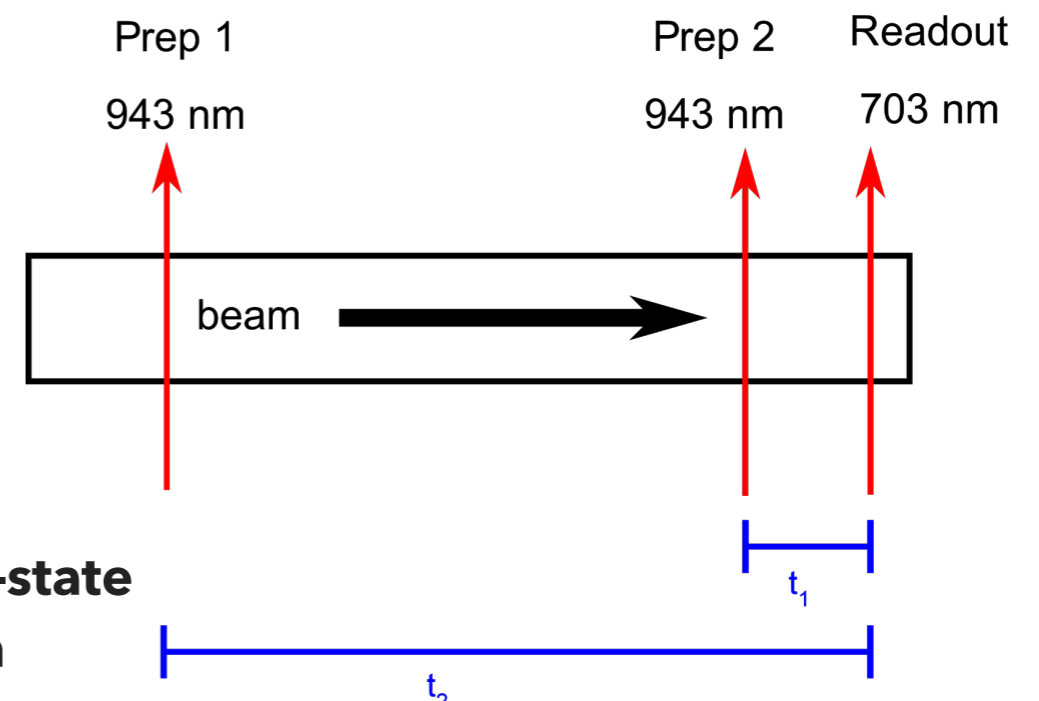
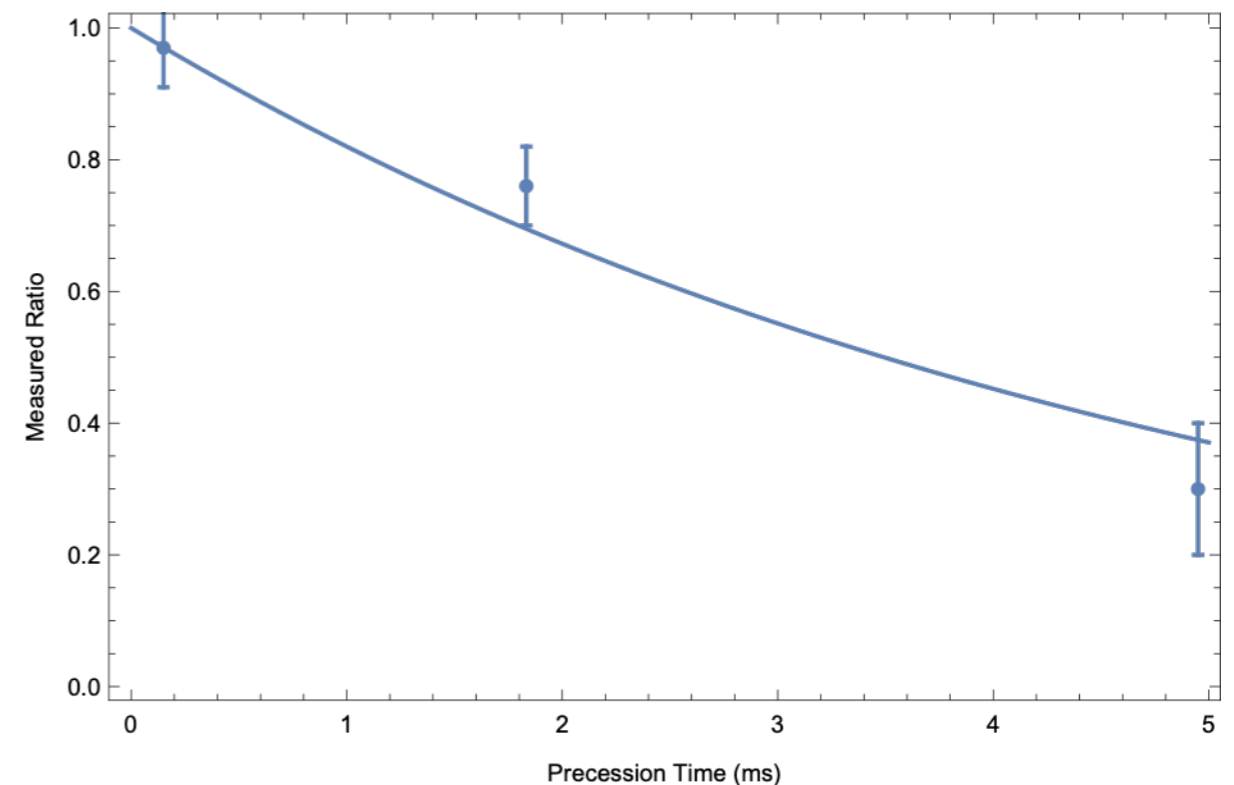
- ▶ Without a lens, fewer than .04% of molecules reach the detector
- ▶ Electrostatic lens focuses molecules into the EDM region, giving **~20x** gain in signal (including the efficiency of double-STIRAP)
- ▶ Efficient STIRAP into the Q state allows for strong focusing



See Poster K01.00142 : Upgrading the ACME electron EDM search with a molecular lens

INCREASED H-STATE LIFETIME

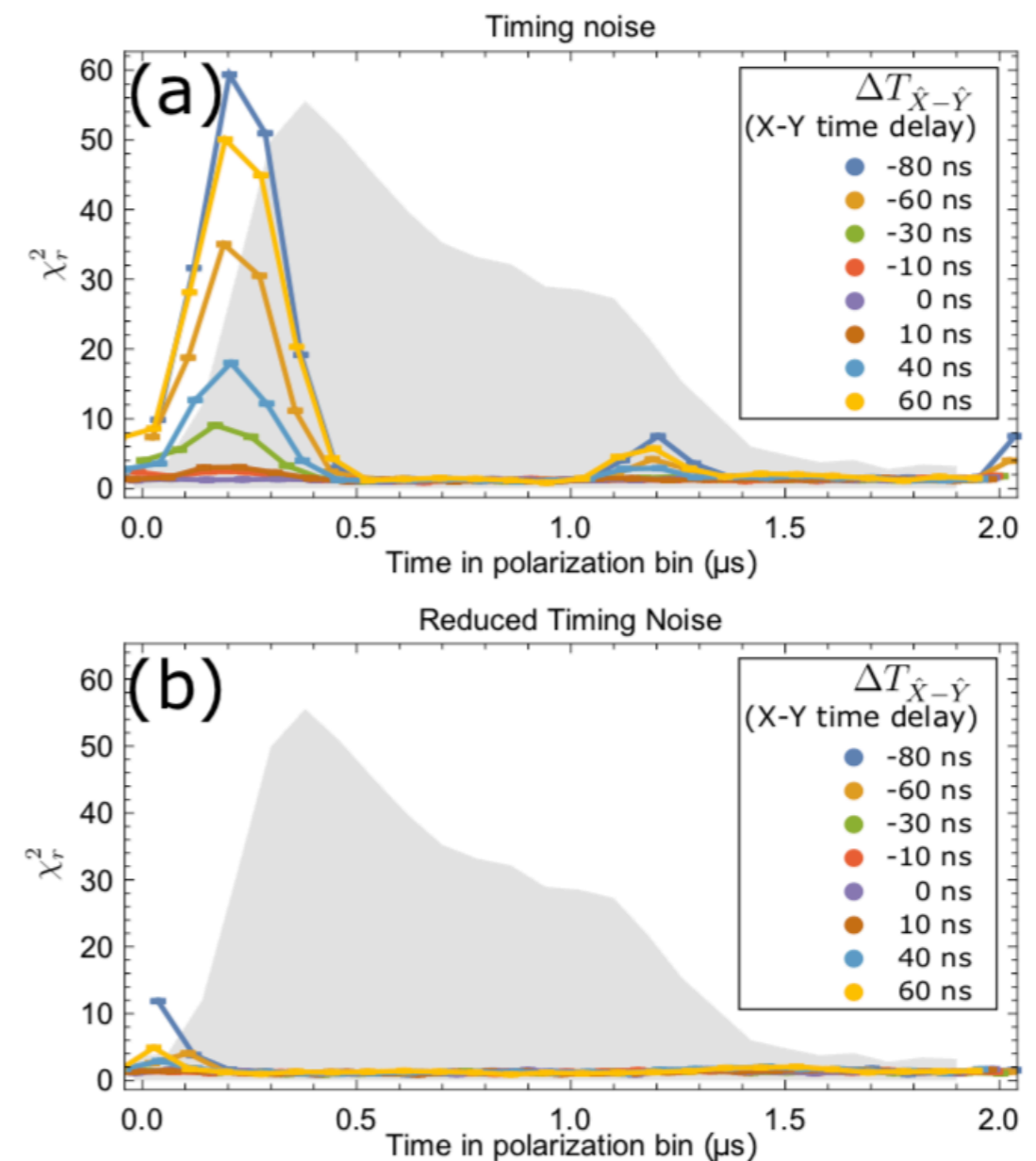
- ▶ Last lifetime measurement showed a lower bound of just 1.8 ms
- ▶ ACME II used only 1 ms (20 cm) precession time
- ▶ Recent measurements suggest a lifetime of approximately **5 ms**
- ▶ Currently working on measurement to reduce uncertainty of H-state lifetime



See the immediately following talk: **H07.00002 : New H-state lifetime measurement for the ACME electron EDM search**

CONTROLLING EXCESS NOISE FOR ADVANCED ACME

- ▶ ACME II had 1.7 times more noise than expected from the shot noise limit
- ▶ Noise came from 2 effects:
 - ▶ Large scale timing jitter
 - ▶ Timing offset between X and Y polarization bins
- ▶ We can now control both parameters to reduce this noise



DETECTION UPGRADES

- ▶ SiPMs provide a significant gain over the PMTs used in ACME II
- ▶ Dark count rate has been controlled in prototype tests

	Requirement	Measured	Comment
Photon detection efficiency	~ 50%	PMT × 2.5	Absolute value is unknown.
Dark count rate	< 10 Mcps	< 10 Mcps	Cooled down to -10°C
Cross talk & After pulse	< 25%	~ 20%	Array type package.
3dB Bandwidth	5 MHz	8.5 MHz	w/ Pole-Zero Cancellation
Electrical noise	< 10 nV/√Hz	< 10 nV/√Hz	

See Poster E01.00160 : Development of a silicon photomultiplier module for ACME III

SYSTEMATIC ERROR CONTROL

- ▶ Working to control systematic errors observed in ACME II
- ▶ Improved magnetic field control
 - ▶ New magnetic shielding
 - ▶ Also reduces noise from beam velocity dispersion
- ▶ Reducing stress induced birefringence in field plates

Table 1 | Systematic shifts for $\omega^{\mathcal{N}\mathcal{E}}$ and their statistical uncertainties

Parameter	Shift	Uncertainty
$\partial\mathcal{B}_z/\partial z$ and $\partial\mathcal{B}_z/\partial y$	7	59
$\omega_{\text{ST}}^{\mathcal{N}\mathcal{E}}$ (via $\theta_{\text{ST}}^{\text{H-C}}$)	0	1
$P_{\text{ref}}^{\mathcal{N}\mathcal{E}}$	–	109
\mathcal{E}^{nr}	–56	140
$C^{\mathcal{N}\mathcal{E}}$ and $ C ^{\mathcal{N}\mathcal{E}\mathcal{B}}$	77	125
$\omega^{\mathcal{E}}$ (via $\mathcal{B}_z^{\mathcal{E}}$)	1	1
Other magnetic-field gradients (4)	–	134
Non-reversing magnetic field, $\mathcal{B}_z^{\text{nr}}$	–	106
Transverse magnetic fields, $\mathcal{B}_x^{\text{nr}}, \mathcal{B}_y^{\text{nr}}$	–	92
Refinement- and readout-laser detunings	–	76
\mathcal{N} -correlated laser detuning, $\Delta^{\mathcal{N}}$	–	48
Total systematic	29	310
Statistical uncertainty		373
Total uncertainty		486

Values are shown in $\mu\text{rad s}^{-1}$. All uncertainties are added in quadrature. For $\mathcal{E}_{\text{eff}} = 78 \text{ GV cm}^{-1}$, $d_e = 10^{-30}e \text{ cm}$ corresponds to $|\omega^{\mathcal{N}\mathcal{E}}| = \mathcal{E}_{\text{eff}}d_e/\hbar = 119 \mu\text{rad s}^{-1}$.

Table from: ACME Collaboration et al., Improved Limit on the Electric Dipole Moment of the Electron, *Nature* (2018).

ADVANCED ACME PROPOSED GAINS

$$\delta d_e = \frac{1}{2T \mathcal{E}_{eff} \sqrt{N}}$$

Improvement	Signal Gain	EDM Sensitivity Gain
Increased Precession Time	0.20	2.3
Electrostatic Lens	20.5	4.5
SiPM Detector Upgrade	2.3	1.5
Timing Jitter Noise Reduction	1	1.7
Total	9.4	26.4

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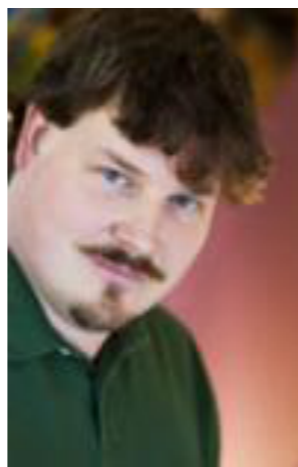
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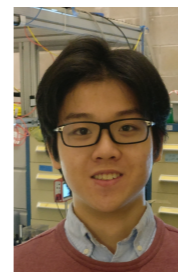
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